IEC/TR 61967-1-1

Edition 1.0 2010-05

TECHNICAL REPORT

RAPPORT TECHNIQUE

colour inside

Integrated circuits – Measurement of electromagnetic emissions – Part 1-1: General conditions and definitions – Near-field scan data exchange format

Circuits intégrés – Mesure des émissions électromagnétiques – Partie 1-1: Conditions générales et définitions – Format d'échange de données de cartographie en champ proche

IEC/TR 61967-1-1:2010

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC EMISSIONS –

Part 1-1: General conditions and definitions – Near-field scan data exchange format

FOREWORD

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IEC 61967-1-1, which is a technical report, has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this technical report is based on the following documents:

Enquiry draft	Report on voting
47A/827A/DTR	47A/833/RVC

Full information on the voting for the approval of this technical report can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 61967 series under the general title *Integrated circuits – Measurement of electromagnetic emissions* can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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INTRODUCTION

Near-field scan measurements, as described for example in IEC 61967-3, and simulations generate a large amount of data. Many different formats are used for storing the data, thereby rendering its exchange extremely difficult.

The proposed format is intended to facilitate exchange of near-field scan data between industrials, academics, EDA tool vendors and end customers. It is based on the well-known XML format, which is both machine and human readable. Its structure allows the files to be generated and processed on any operating system. In order to limit the file size, it is possible to store the information and data in a single file or multiple files. Moreover, the ASCII-based XML format allows the files to be compressed to a very high level with readily available compression software.

The three conventional coordinate systems (cartesian, cylindrical and spherical) are supported by the proposed exchange format. Information on the device under test, the test set-up, the probe, etc., is also included in the files. Notes and links to external documents allow complex test environments to be well described.

The version of the exchange format described in this technical report is 1.0. Future revisions will add items, such as new keywords and rules, considered to be "enhancements" to Version 1.0. Consequently, all future revisions will be considered supersets of Version 1.0, allowing backward compatibility.